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# **bq25871 14-V, 7-A, Battery Switch Charger with Integrated 10-bit ADC**

**Technical** [Documents](http://www.ti.com/product/bq25871?dcmp=dsproject&hqs=td&#doctype2)

## <span id="page-0-1"></span>**1 Features**

- <sup>1</sup> Adapter Input Voltage Range: 3 V to 14 V
	- Allow up to 14-V Adaptor Voltage
	- Highly Integrated 7-A Battery Switch
	- Integrated MOSFETs and Current Sensing
	- Low R<sub>DS(on)</sub> (13-mΩ) MOSFETs for High Current Operation
- Integrated High Accuracy ADC for System Monitor
	- VBUS, VBAT, VOUT, VDROP Voltage
	- Input and Battery Current
	- Battery and VBUS Connector Temperature
- Linear Regulation (LDO) Mode Operation
	- Four Linear Regulation Loops: IBUS, IBAT, VBAT and VOUT
	- Programmable Linear Regulation Thresholds
- Programmable Safety Protections
	- VBUS, VOUT, and VBAT Over Voltage Protections (OVP)
	- IBUS and IBAT Over Current Protection (OCP)
	- IBUS Reverse Current Protection (RCP)
	- VDROP (VBUS-VOUT) OVP
	- VBUS Connector and Battery Thermal Protection
	- Thermal Shutdown
- Interrupt Status Output For Host Processor Alert
- Up To 1-MHz I<sup>2</sup>C Read and Write Speed
- Low Battery Leakage Current in Battery Only Mode
- <span id="page-0-0"></span>• WCSP Package for Small Footprint

# <span id="page-0-2"></span>**2 Applications**

- **Smart Phone**
- Tablet PC

# **3 Description**

Tools & **[Software](http://www.ti.com/product/bq25871?dcmp=dsproject&hqs=sw&#desKit)** 

The device is a 7-A battery switch charger with an integrated 10-bit ADC. The high-current battery switch charger is a 13-mΩ MOSFET with reverse current blocking designed for high efficiency and minimal voltage drop. The high-charge current capability of the device makes it ideal for smartphones, tablets, and other portable devices with large battery capacity.

Support & **[Community](http://www.ti.com/product/bq25871?dcmp=dsproject&hqs=support&#community)** 

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The integrated 10-bit ADC can measure input voltage and current, battery voltage and current, as well as battery temperature and input connector temperature. This allows the user application to continuously monitor the power input and battery charging parameters to ensure the safety of the battery charging. The flexible OVP and OCP thresholds for VBUS, VOUT, and battery can be modified via  $I^2C$ registers as the battery goes through constant current (CC) and constant voltage (CV) mode.

The I<sup>2</sup>C serial interface of the device can operate at speeds up to 1 MHz and allows access to the ADC's measurements of the different charging parameters and also allows for flexible software control of the device. The INT pin provides instantaneous feedback to the host in case of a fault condition.  $I^2C$  status registers allow the host to read the current status of all faults and events.

The device comes in a DSBGA package.

#### **Device Information[\(1\)](#page-0-0)**



(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### **Simplified Schematic**





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# **5 Pin Configuration and Functions**

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kja.

#### **Pin Functions**





# <span id="page-4-0"></span>**6 Specifications**

### <span id="page-4-1"></span>**6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>



(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### <span id="page-4-2"></span>**6.2 ESD Ratings**



(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

# <span id="page-5-0"></span>**6.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)



## <span id="page-5-1"></span>**6.4 Thermal Information**



(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, [SPRA953.](http://www.ti.com/lit/pdf/spra953)

#### <span id="page-6-0"></span>**6.5 Electrical Characteristics**



















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# <span id="page-11-0"></span>**6.6 Timing Requirements**





# **7 Typical Characteristics**

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# <span id="page-14-0"></span>**8 Detailed Description**

## <span id="page-14-1"></span>**8.1 Overview**

The bq25871 is an I<sup>2</sup>C controlled device and a single cell Li-Ion battery charger. The device allows 7-A charging current with 13-mΩ MOSFETs for minimum power loss. A 10 -bit ADC, four linear regulation loops and multiple OVP and OCP are integrated for host monitoring and safe operation of the device.

#### **8.1.1 Device Protection Overview**

The following table summarizes the protection features implemented in the device.



#### **Table 1. Protection Features Overview**

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# <span id="page-15-0"></span>**8.2 Functional Block Diagram**



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#### <span id="page-16-0"></span>**8.3 Feature Description**

# **8.3.1 Device Power Up**

The internal bias circuits of the device are powered from higher of the two voltages between VBUS and VOUT as long as one of the pins is above its respective PRESENT threshold (VBUS<sub>PRESENT</sub>, or VOUT<sub>PRESENT</sub>). Once either  $V_{VBUS}$  > VBUS<sub>PRESENT</sub>, or  $V_{VOUT}$  > VOUT<sub>PRESENT</sub> is qualified, the device is considered to have a valid power supply. However, the device will begin to draw current from VBUS or VOUT (depending upon which supply is present) once either supply is above its respective UVLO threshold.

# **8.3.2 Battery Switch (Q1 + Q2)**

The device contains an integrated 13mΩ battery switch that is capable of handling up to 7 A of current. This battery switch can be controlled by the host via CHG\_EN I<sup>2</sup>C bit. The device can be disabled, including the battery switch and the I<sup>2</sup>C core, by pulling the EN pin low. To turn on the battery switch charger for conduction, the EN pin must be pulled high, CHG\_EN bit must be set to '1', and no fault conditions must be present (unless they have been disabled in EVENT 1 EN register). See EVENT 1 and EVENT 2 registers for a list of faults/events. In the event of a fault/event, the battery switch will be automatically disabled, and the host will be notified via the INT for error reporting if the corresponding event bit is unmasked in the EVENT x MASK registers.

In order to ensure that the IBUS OCP threshold is not falsely tripped during turn-on of the battery switch, the device employs a soft-start scheme where the battery switch is slowly turned to minimize the inrush current. The rise time of VOUT is  $t_{ON}$  <sub>VOUT</sub>.

# **8.3.3 Integrated 10-bit ADC for Monitoring**

With the integrated 10-bit ADC of the device, the user application can monitor , the voltage and current of VBUS, voltage of VOUT , and the voltage and current of the battery. The ADC is also used for temperature reporting of the internal junction temperature, battery temperature (via external resistor divider and NTC thermistor), and VBUS connector temperature (via external resistor divider and NTC thermistor). The integrated ADC has a conversion time of  $t_{ADC}$  conv for each parameter (except IBAT\_ADC which has conversion time of 2 x  $t_{ADC,CONV}$ ). The total conversion time of all parameters (in 1-shot mode) is between 80 µs and 140 µs. The rate at which the ADC output registers are updated depends on the settings of ADC\_AVG\_EN, ADC\_SAMPLES, and the parameter conversions that have been enabled in the ADC\_MASK register.

To enable the ADC, the ADC\_EN bit must be set to '1'. The ADC is allowed to operate if either  $V_{VBUS}$  > VBUS<sub>PRESENT</sub> or  $V_{VOUT} > VOUT_{PRESENT}$  is valid. If ADC\_EN is set to '1' before VBUS or VOUT reach their respective PRESENT threshold, then ADC conversion will be postponed until one of the power supplies reaches their respective PRESENT threshold. If EN pin is asserted low, then ADC conversion is not allowed.

The integrated ADC has two conversion rate options – 1-shot conversion (only one conversion) and continuous conversion (back-to-back conversions). To select the appropriate conversion rate, the ADC\_RATE bit must be set accordingly ('0' for 1-shot, '1' for continuous). If ADC\_AVG\_EN is set to '0', the ADC will convert instantaneous measurements. If ADC\_AVG\_EN is set to '1', the average measurement of a parameter (in both continuous and 1-shot mode) will be determined by the setting of ADC\_SAMPLES. If the user reads the output registers before the ADC averaging is complete, then the read-back value would be unchanged from the previous converted measurement. However, the value in the register will not change during the read-back of the register(s). If the measured signal is outside of the range of the ADC output register in question, the reported value in the ADC will be clamped to the min/max of the range specified. When ADC\_EN is changed from 1 to 0, the ADC registers will maintain their values from the previous converted measurement.



The user application has the option of selecting which parameters (voltage, current, temperature) the ADC needs to convert when the ADC is set to continuous conversion mode (ADC\_RATE is set to '1') or in 1-shot mode (ADC\_RATE is set to '0'). By default, all parameters ( IBUS\_ADC, VBUS\_ADC, IBAT\_ADC, VBAT\_ADC, VOUT\_ADC, VDROP\_ADC, TBUS\_ADC, TBAT\_ADC, TDIE\_ADC) will be converted in 1-shot and continuous conversion mode unless disabled in the ADC\_MASK register. If an ADC parameter is masked (by setting the corresponding bit in the ADC\_MASK\_x register), then the value in that register will be from the last valid ADC conversion or the default POR value (which is all zeros if no conversions have taken place). If an ADC parameter is masked in the middle of an ADC measurement cycle, the device will finish the conversion of that parameter in the current conversion cycle and will not convert that parameter starting the next conversion cycle. Even though no conversion takes place when all ADC measurement parameters are masked off, the ADC circuitry is active and ready to begin conversion as soon as one of the bits in the ADC\_MASK register is set to '0'.

The ADC\_DONE bit signals when a 1-shot mode conversion is completed. During continuous conversion mode, this bit is always set to '0'.

The ADC EN bit controls when the ADC is enabled for a conversion. Upon enabling the ADC, the ADC conversion will follow the settings in ADC\_AVG\_EN, ADC\_SAMPLE, and ADC\_RATE.

ADC conversion operates independently of the faults present in the device. ADC conversion will continue even after a fault has occurred (that causes the battery switch to be disabled), and the host must set ADC  $EN = '0'$  to disable ADC.

ADC readings are only valid for DC states of the signals, not for transients.

#### **8.3.4 Linear Regulation Mode (LDO)**

The device employs LDO mode that helps regulate VOUT voltage, battery voltage, input current and battery current. In an event that the VOUT\_REG, VBAT\_REG, IBUS\_REG or IBAT\_REG threshold is exceeded, the battery switch will act as an LDO and will regulate VOUT, VBAT, IBUS and IBAT (depending upon which threshold is exceeded). The purpose of LDO mode is to provide temporary protection until the host is able to read the EVENT x registers (upon  $\overline{INT}$  trigger), ADC output registers, and then update the adapter voltage accordingly.

When VOUT REG, VBAT REG, or IBAT REG threshold is exceeded, the response time of the LDO will be 1ms. Depending upon which LDO mode event occurs, the corresponding bit (VBAT\_REG\_LDO, IBAT\_REG\_LDO, VOUT\_REG\_LDO) will be set in EVENT\_1 register and INT will be asserted low to alert the host (if the corresponding bit is not masked in EVENT 1 MASK register).



# **8.3.5 Protection Features**

The device contains various protection features that are active depending upon the states of various inputs:

- If  $V_{VBUS}$  > VBUS<sub>PRESENT</sub>,  $V_{VOUT}$  > VOUT<sub>PRESENT</sub>, EN asserted high, and CHG\_EN = '1'
	- Active protection: VBUS\_OVP, IBUS\_OCP, VOUT\_OVP, VBAT\_OVP, IBAT\_OCP, SCP, RCP, VDROP\_OVP
- If  $V_{VBUS}$  > VBUS<sub>PRESENT</sub>,  $V_{VOUT}$  > VOUT<sub>PRESENT</sub>, EN asserted high, and CHG\_EN = '0'
	- Active protection: VBUS\_OVP, IBUS\_OCP, VOUT\_OVP, IBAT\_OCP, SCP, RCP, VDROP\_OVP
	- VBAT\_OVP active until VBAT OVP condition is over (protection becomes inactive on falling threshold of VBAT\_OVP, which is 102% of VBAT\_REG setting)

Tripping any of these protection faults will cause the battery switch to be disabled (unless the protection is disabled in EVENT\_1\_EN and EVENT\_2\_EN registers) and an interrupt to be issued on the INT pin (see INT Pin, EVENT\_x Registers, EVENT\_x\_MASK Registers section for details of when INT is toggled).

# *8.3.5.1 Reverse Current Protection (RCP)*

The device monitors the current flow from VBUS to VOUT to ensure there is no reverse current (current flow from VOUT to VBUS). In an event that a reverse current flow is detected, the battery switch is disabled within  $t_{OFF}$  after a deglitch time of  $t_{IRFV}$  and CHG\_EN is set to '0'. Host intervention is required to set CHG\_EN to '1' to enable the power switch again. The RCP threshold is set by the RCP\_SET bit.

Reverse current protection is always active when the device has valid power. The RCP threshold is based on the RCP\_SET bit setting in the CONTROL register. It has a response delay of  $t_{IRFV}$ . When RCP is tripped, IBUS IREV FLT bit in the EVENT 1 register is set to '1', and INT is asserted low to alert the host (unless masked by IBUS\_IREV\_MASK).

# *8.3.5.2 Internal Thermal Shutdown*

The device monitors the die junction temperature and the battery switch is disabled when device junction temperature reaches TSHUT within  $t_{DEF}$  and CHG\_EN is set to '0'. When the internal thermal shutdown is triggered,  $\overline{\text{INT}}$  is asserted low to alert the host, and the device temperature must drop by TSHUT\_HYS before the battery switch can be enabled again (host must enable battery switch). While the TSHUT condition persists (and before the junction temperature dropped by TSHUT\_HYS), all other functions are unaffected.

If the DIE\_TEMP\_FLT threshold has been crossed, TSHUT\_FLT bit in EVENT\_2 register is set to '1', and  $\overline{\text{INT}}$ will assert low to alert the host (no mask bit for TSHUT\_FLT). After the TSHUT\_FLT is cleared by the host with a register read, it is possible the TSHUT\_FLT bit is set again if the die junction temperature has not reduced by TSHUT\_HYS.

DIE\_TEMP\_FLT allows the user to select TSHUT thresholds between different junction temperatures as the thermal shutdown point. DIE\_TEMP\_ADC is the die (junction) temperature of the device that is measured via the 10-bit ADC.

The ADC measurement (DIE\_TEMP\_ADC) is independent of the TSHUT fault that triggers TSHUT\_FLT in the EVENT\_x register. Therefore, it is possible to have the ADC output value be a higher value that the DIE\_TEMP\_FLT threshold, while the TSHUT fault has not yet been triggered.



#### *8.3.5.3 IBUS and VBUS Protection*

Over-current protection on VBUS (IBUS\_OCP) monitors the current flow from VBUS to VOUT pins. IBUS\_OCP protection is always active when the battery switch is enabled, and the protection has a deglitch time that depends on the OCP\_RES setting as described below.

If OCP\_RES = '0' (blanking mode), the device will wait  $t_{IBUS\_OCP_BLANK}$  before disabling the battery switch within  $t_{OFF}$  and setting CHG\_EN to '0'. When the battery switch is disabled, IBUS\_OCP\_FLT is set to '1'. If during the t<sub>IBUS</sub> <sub>OCP</sub> BLANK duration a short circuit protection scenario occurs, then the device will follow the behavior as listed in short circuit protection (SCP). Once the battery switch is disabled, CHG\_EN is set to '0' and host intervention is required to set CHG EN to '1' to enable the battery switch again.



**Figure 11. IBUS OCP and SCP**



If OCP\_RES = '1' (hiccup mode), the device will turn off the battery switch within t<sub>IBUS</sub> <sub>OCP</sub> and will attempt to turn on the battery switch every t<sub>IBUS\_OCP\_HP</sub>, up to seven times before latching off the battery switch. Upon latching off after the seventh try, IBUS\_OCP\_FLT is set to '1'. Once the battery switch is latched off, CHG\_EN is set to '0' and host intervention is required to set CHG\_EN to '1' to enable the battery switch again.



**Figure 12. IBUS OCP in Hiccup Mode**

VBUS over-voltage protection (VBUS\_OVP) monitors the voltage on VBUS. VBUS\_OVP protection is always active when the device voltage is above at least one PRESENT level (VBUS or VOUT), and the protection has a selectable deglitch time set by VBUS\_OVP\_DLY. When VBUS\_OVP threshold is reached, the battery switch is turned off in t<sub>VBUS\_OVP</sub> and latched off. If the VBUS\_OVP or IBUS\_OCP value written to the register is greater than the max defined value for the register, then the corresponding register will be set to the highest defined value.

If a threshold has been crossed (IBUS OCP or VBUS OVP), the appropriate bit in the EVENT 1 register is updated (set to '1' if threshold is crossed, '0' if threshold is not crossed). If the EVENT\_1\_MASK bit is not set to '1' for the corresponding bit in the EVENT\_1 register, then INT will assert low to alert the host of a fault.



#### *8.3.5.4 IBAT and VBAT Protection*

The device monitors current through the battery by monitoring the voltage across the external, series battery sense resistor. The differential voltage of this sense resistor is measured on SRP and SRN. A 10-mΩ series resistor is recommended for battery current monitoring. A lower resistor value can be used, but it will result in lower measurement accuracy. A higher resistor value can be used, but it will result in decreased charging efficiency.

When the IBAT\_REG threshold is reached, the device will go into LDO mode to regulate the battery current at the IBAT\_REG threshold. See LDO mode section for more details about the device operation during LDO mode. If the IBAT OCP threshold is reached and IBAT OCP protection has been enabled, the battery switch will be disabled within t<sub>OFF FET</sub> after a deglitch time of t<sub>IBAT</sub> <sub>OCP</sub> and CHG\_EN is set to '0'. Host intervention is required to set CHG\_EN to '1' to enable the battery switch again.

The device monitors battery voltage by measuring the differential voltage on BATP and BATN pins. When the VBAT REG threshold is reached, the device will go into LDO mode to regulate the battery voltage at the VBAT\_REG threshold. See LDO mode section for more details about the device operation during LDO mode. If the VBAT\_OVP threshold is reached and VBAT\_OVP protection is enabled, the battery switch will be disabled within t<sub>OFF FET</sub> after a deglitch time of t<sub>VBAT</sub> <sub>OVP</sub> and CHG\_EN is set to '0'. Host intervention is required to set CHG\_EN to '1' to enable the battery switch again. If the VBAT\_REG or IBAT\_REG value written to the register is greater than the max defined value for the register, then the corresponding register will be set to the highest defined value.

If a threshold has been reached (IBAT\_REG, VBAT\_REG, IBAT\_OCP or VBAT\_OVP), the appropriate bit in the EVENT x register is updated (set to '1' if threshold is crossed, '0' if threshold is not crossed). If the EVENT\_x\_MASK bit is not set to '1' for the corresponding bit in the EVENT\_x register, then INT will assert low to alert the host of a fault.

#### *8.3.5.5 VOUT Protection*

The device monitors voltage on VOUT when the device has a valid power supply. When the VOUT\_REG threshold is reached, the device will go into LDO mode to regulate the VOUT voltage at the VOUT REG threshold. See LDO mode section for more details about the device operation during LDO mode. If the VOUT\_OVP threshold is reached and VOUT\_OVP protection is enabled, the battery switch will be disabled within t<sub>OFF FET</sub> after a deglitch time of t<sub>VOUT</sub> <sub>OVP</sub> and CHG\_EN is set to '0'. Host intervention is required to set CHG\_EN to '1' to enable the battery switch again. If the VOUT\_REG value written to the register is greater than the max defined value for the register, then VOUT\_REG will be set to the highest defined value for the register.

If a threshold has been reached (VOUT\_REG or VOUT\_OVP), the appropriate bit in the EVENT\_1 register is updated (set to '1' if threshold is crossed, '0' if threshold i<u>s no</u>t crossed). If the EVENT\_x\_MASK bit is not set to '1' for the corresponding bit in the EVENT\_x register, then INT will assert low to alert the host of a fault.



#### *8.3.5.6 VDROP Protection*

VDROP is the voltage difference from VBUS to VOUT and can be used to monitor the health of MOSFET and power loss of the device. There are two VDROP thresholds, VDROP alarm (VDROP\_ALM) and VDROP fault (VDROP\_FLT). VDROP\_ALM is an indicator (via  $I^2C$  register bit and  $\overline{INT}$ ) to alert the host that the voltage differential between VBUS and VOUT is higher than normal, and that the host to should take action to reduce this drop. VDROP\_OVP is a fault threshold that results in the battery switch being disabled within t<sub>OFF-FET</sub> after a

deglitch time of t<sub>VDROP\_OVP</sub> and CHG\_EN set to '0' when VDROP\_OVP protection is enabled. Host intervention is required to set CHG\_EN to '1' to enable the battery switch again. If the VDROP\_OVP or VDROP\_ALM value written to the register is greater than the max defined value for the register, then the corresponding register will be set to the highest defined value.

If a threshold has been reached (VDROP\_ALM or VDROP\_OVP), the appropriate bit in the EVENT\_1 register is updated (set to '1' if threshold is crossed, '0' if threshold is not crossed). If the EVENT x MASK bit is not set to '1' for the corresponding bit in the EVENT\_x register, then INT will assert low to alert the host of a fault.

VDROP ALM does not affect the state of the battery switch and only causes  $\overline{\text{INT}}$  to assert low when the threshold is crossed. VDROP\_OVP does turn off the battery switch and causes INT to assert low if this threshold is crossed. Therefore, if VDROP\_ALM threshold is set higher than the VDROP\_OVP threshold accidentally (user error), then VDROP\_ALM functionality is never triggered since VDROP\_OVP threshold will turn off the battery switch and assert INT low.

#### **NOTE**

The threshold of VDROP\_OVP and VDROP\_ALM is around 13 mV lower than the actual setting when VDROP ADC is enabled.

#### *8.3.5.7 VBUS Temperature (TS\_BUS\_FLT) and Battery Temperature (TS\_BAT\_FLT)*

TBUS OTP and TBAT OTP protection is active whenever the device has a valid power supply. The purpose of VBUS temperature is to have connector temperature monitor to improve user experience. TS\_BUS and TS\_BAT both rely on a resistor divider that has an external pull-up voltage. Internally, the TS\_BUS and TS\_BAT pins are clamped to 2.42 V. Place a negative coefficient thermistor in parallel to the low-side resistor. A fault on the TS BUS and TS BAT pin is triggered on the falling edge of the voltage threshold (signifying a "hot" temperature).

If the TBUS\_OTP or TBAT\_OTP threshold is reached, the battery switch will be disabled within  $t_{OFF-FET}$  after a deglitch time of t<sub>TS OTP</sub> and CHG\_EN is set to '0'. Host intervention is required to set CHG\_EN to <sup>'1'</sup> to enable the battery switch again. If the TS\_BUS\_FLT or TS\_BAT\_FLT value written to the register is greater than the max defined value for the register, then the corresponding register will be set to the highest defined value.

For TS BUS FLT and TS BAT FLT, if a threshold has been crossed, the appropriate bit in the EVENT  $x$ register is updated (set to '1' if threshold is crossed, '0' if threshold is not crossed). If the EVENT x MASK bit is not set to '1' for the corresponding bit in the EVENT 1 register, then  $\overline{\text{INT}}$  will toggle to alert the host of a fault.

#### **NOTE**

TS\_BUS\_FLT will not trip when TS\_BUS ADC is enabled.



#### **8.3.6 I<sup>2</sup>C Serial Interface**

The device uses I<sup>2</sup>C compatible interface for flexible charging parameter programming and instantaneous device status reporting. I<sup>2</sup>C communication to the device is available as long as V<sub>VBUS</sub> > VBUS<sub>UVLO</sub>or V<sub>VOUT</sub> > VOUT<sub>UVLO</sub>. I<sup>2</sup>C<sup>™</sup> is a bi-directional 2-wire serial interface developed by Philips Semiconductor (now NXP Semiconductors). Only two bus lines are required, a serial data line (SDA) and a serial clock line (SCL). Devices can be considered as masters or slaves when performing data transfers. A master is the device which initiates a data transfer on the bus and generates the clock signals to permit that transfer. At that time, any device addressed is considered a slave.

The device operates as a slave device with address set by the ADDR pin. The device receives control inputs from the master device like micro controller or a digital signal processor through REG00-REG29 and REG40. Register read between REG29 and REG39 beyond REG40 returns 0xFF. The I<sup>2</sup>C interface supports standard mode (up to 100 kbit/s), fast mode (up to 400 kbit/s), and fast mode plus (up to 1 Mbit/s). Connect the SDA and SCL pins to the positive supply voltage via a current source or pull-up resistor. When the bus is free, both lines are high. The SDA and SCL pins are open drain.

The device supports 7-bit addressing. The 8th bit will change depending upon the command (read or write) that is issued. The device's 7-bit address is defined as shown in the image below.



**Figure 13. Slave Address**

#### *8.3.6.1 Data Validity*

The data on the SDA line must be stable during the HIGH period of the clock. The HIGH or LOW state of the data line can only change when the clock signal on the SCL line is LOW. One clock pulse is generated for each data bit transferred.







#### *8.3.6.2 START and STOP Conditions*

All transactions begin with a START (S) and can be terminated by a STOP (P). A HIGH to LOW transition on the SDA line while SCL is HIGH defines a START condition. A LOW to HIGH transition on the SDA line when the SCL is HIGH defines a STOP condition.

START and STOP conditions are always generated by the master. The bus is considered busy after the START condition, and free after the STOP condition.





#### *8.3.6.3 Byte Format*

Every byte on the SDA line must be 8 bits long. The number of bytes to be transmitted per transfer is unrestricted. Each byte has to be followed by an Acknowledge bit. Data is transferred with the Most Significant Bit (MSB) first. If a slave cannot receive or transmit another complete byte of data until it has performed some other function, it can hold the clock line SCL low to force the master into a wait state (clock stretching). Data transfer then continues when the slave is ready for another byte of data and release the clock line SCL.



**Figure 16. Data Transfer on the I<sup>2</sup>C Bus**

#### *8.3.6.4 Acknowledge (ACK) and Not Acknowledge (NACK)*

The acknowledge takes place after every byte. The acknowledge bit allows the receiver to signal the transmitter that the byte was successfully received and another byte may be sent. All clock pulses, including the acknowledge 9th clock pulse, are generated by the master.

The transmitter releases the SDA line during the acknowledge clock pulse so the receiver can pull the SDA line LOW and it remains stable LOW during the HIGH period of this clock pulse.

When SDA remains HIGH during the ninth clock pulse, this is the Not Acknowledge signal. The master can then generate either a STOP to abort the transfer or a repeated START to start a new transfer.

# *8.3.6.5 Slave Address and Data Direction bit*

After the START, a slave address is sent. This address is 7 bits long followed by the eighth bit as a data direction bit (bit R/W). A zero indicates a transmission (WRITE) and a one indicates a request for data (READ).



## **Figure 18. Single Read**

If the register address is not defined, the charger device send back NACK and go back to the idle state.

#### *8.3.6.6 Multi-Read and Multi-Write*

(

The charger device supports multi-read and multi-write on REG00 through REG08.



**Figure 19. Multi-Read**

EVENT 1, EVENT 2, and EVENT 3 keep all the information from last read until the host issues a new read. For example, if VBUS\_OVP fault occurs but recovers later, the fault register EVENT\_1 reports the fault when it is read the first time, but returns to normal when it is read the second time. In order to get the fault information at present, the host has to read EVENT\_1, EVENT\_2, and EVENT\_3 for the second time.



## <span id="page-26-0"></span>**8.4 Device Functional Modes**

The device is a host controlled device. After power-on-reset, all the registers are in the default settings. All the device parameters can be programmed by the host. Writing 1 to REG 06 [0] will reset all registers to default setting. When watchdog timer expires, charge enable bit (REG06 [4]) and ADC enable bit (REG07 [3]) will be reset to default settings. To prevent watchdog timer expiring, the host has to read or write any register before the watchdog timer expires, or disable watchdog timer by setting REG06 [3:2] = 00.



**Figure 20. Operation Mode**

# <span id="page-27-0"></span>**8.5 I<sup>2</sup>C Register Maps**

# **8.5.1 I<sup>2</sup>C Register Summary Table**

# **Table 2. I<sup>2</sup>C Register Summary Table**



## **8.5.2 REG00 (DEVICE\_INFO)**

# **[bq25871](http://www.ti.com/product/bq25871?qgpn=bq25871) [www.ti.com](http://www.ti.com)** SLUSCQ5-OCTOBER 2016

# **Figure 21. REG00 (DEVICE\_INFO)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 3. REG00 (DEVICE\_INFO)**



**ISTRUMENTS** 

Texas

## **8.5.3 REG01 (EVENT\_1\_MASK)**

### **Figure 22. REG01 (EVENT\_1\_MASK)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 4. REG01 (EVENT\_1\_MASK)**



### **8.5.4 REG02 (EVENT\_2\_MASK)**

# **Figure 23. REG02 (EVENT\_2\_MASK)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 5. REG02 (EVENT\_2\_MASK)**



# **8.5.5 REG03 (EVENT\_1)**

# **Figure 24. REG03 (EVENT\_1)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 6. 6.4.5 REG03 (EVENT\_1)**



# **8.5.6 REG04 (EVENT\_2)**

### **[bq25871](http://www.ti.com/product/bq25871?qgpn=bq25871) [www.ti.com](http://www.ti.com)** SLUSCQ5 –OCTOBER 2016

# **Figure 25. REG04 (EVENT\_2)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 7. REG04 (EVENT\_2)**



### **8.5.7 REG05 (EVENT\_1\_EN)**

# **Figure 26. REG05 (EVENT\_1\_EN)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 8. REG05 (EVENT\_1\_EN)**



# **8.5.8 REG06 (CONTROL)**

#### **[bq25871](http://www.ti.com/product/bq25871?qgpn=bq25871) [www.ti.com](http://www.ti.com)** SLUSCQ5 –OCTOBER 2016

# **Figure 27. REG06 (CONTROL)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 9. REG06 (CONTROL)**



**ISTRUMENTS** 

Texas

### **8.5.9 REG07 (ADC\_CONTROL)**

# **Figure 28. REG07 (ADC\_CONTROL)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 10. REG07 (ADC\_CONTROL)**



#### **8.5.10 REG08 (ADC\_EN)**

### **[bq25871](http://www.ti.com/product/bq25871?qgpn=bq25871) [www.ti.com](http://www.ti.com)** SLUSCQ5-OCTOBER 2016

# **Figure 29. REG08 (ADC\_EN)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 11. REG08 (ADC\_EN)**



Texas **NSTRUMENTS** 

#### **8.5.11 REG09 (PROTECTION)**

#### **Figure 30. REG09 (PROTECTION)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 12. REG09**



### **8.5.12 REG0A (VBUS\_OVP)**

## **Figure 31. REG0A (VBUS\_OVP)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 13. REG0A (VBUS\_OVP)**



## **8.5.13 REG0B (VOUT\_REG)**

# **Figure 32. REG0B (VOUT\_REG)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 14. REG0B (VOUT\_REG)**



#### **8.5.14 REG0C (VDROP\_OVP)**

#### **Figure 33. REG0C (VDROP\_OVP)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 15. REG0C (VDROP\_OVP)**



#### **8.5.15 REG0D (VDROP\_ALM)**

#### **Figure 34. REG0D (VDROP\_ALM)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 16. REG0D (VDROP\_ALM)**



#### **8.5.16 REG0E (VBAT\_REG)**

#### **Figure 35. REG0E (VBAT\_REG)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 17. REG0E (VBAT\_REG)**



#### **8.5.17 REG0F (IBAT\_REG)**

#### **Figure 36. REG0F (IBAT\_REG)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 18. REG0F (IBAT\_REG)**





# **8.5.18 REG10 (IBUS\_REG)**

# **Figure 37. REG10 (IBUS\_REG)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

## **Table 19. REG10 (IBUS\_REG)**

**Description**

**Reset**

**REG\_RST Watchdog EN**

# **8.5.19 REG11 (TS\_BUS\_FLT)**

Bit Field Type

### **Figure 38. REG11 (TS\_BUS\_FLT)**



LEGEND:  $R/W = Read/Write$ ;  $R = Read$  only; -n = value after reset

#### **Table 20. REG11 (TS\_BUS\_FLT)**



### **8.5.20 REG12 (TS\_BAT\_FLT)**

#### **Figure 39. REG12 (TS\_BAT\_FLT)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 21. REG12 (TS\_BAT\_FLT)**



#### **8.5.21 REG 13 and REG 14 (VBUS\_ADC)**

#### **Figure 40. REG 13 and REG 14 (VBUS\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 22. REG 13 and REG 14 (VBUS\_ADC)**



#### **8.5.22 REG15 and REG16 (IBUS\_ADC)**

# **Figure 41. REG15 and REG16 (IBUS\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 23. REG15 and REG16 (IBUS\_ADC)**





#### **8.5.23 REG17 and REG18 (VOUT\_ADC)**

# **Figure 42. REG17 and REG18 (VOUT\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 24. REG17 and REG18 (VOUT\_ADC)**



#### **8.5.24 REG19 and REG1A (VDROP\_ADC)**

# **Figure 43. REG19 and REG1A (VDROP\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 25. REG19 and REG1A (VDROP\_ADC)**





### **8.5.25 REG1B and REG1C (VBAT\_ADC)**

# **Figure 44. REG1B and REG1C (VBAT\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 26. REG1B and REG1C (VBAT\_ADC)**



# **8.5.26 REG1D and REG1E (IBAT\_ADC)**

# **Figure 45. REG1D and REG1E (IBAT\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

### **Table 27. REG1D and REG1E (IBAT\_ADC)**





#### **8.5.27 REG1F and REG20 (TS\_BUS\_ADC)**

# **Figure 46. REG1F and REG20 (TS\_BUS\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 28. REG1F and REG20 (TS\_\_BUS\_ADC)**



## **8.5.28 REG21 and REG22 (TS\_BAT\_ADC)**

#### **Figure 47. REG21 and REG22 (TS\_BAT\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 29. REG21 and REG22 (TS\_BAT\_ADC)**



#### **8.5.29 REG 23 (TDIE\_ADC)**

#### **Figure 48. REG23 (TDIE\_ADC)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 30. REG23 (TDIE\_ADC)**



# **Figure 49. REG24 (EVENT\_2\_EN)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 31. REG24 (EVENT\_2\_EN) (0x24 Register)**



#### **8.5.31 REG 25 (EVENT\_3\_MASK)**

#### **Figure 50. REG25 (EVENT\_3\_MASK)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

#### **Table 32. REG26 (EVENT\_3\_MASK) (0x026 Register)**



# **Figure 51. REG26 (EVENT\_3)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 33. REG26 (EVENT\_3) (0x26 Register)**



#### **8.5.33 REG 29 (CONTROL\_2)**

# **Figure 52. REG29 (CONTROL\_2)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 34. REG29 (RSENSE) (0x29 Register)**



# **8.5.34 REG 40 (DIE\_TEMP\_FLT)**

#### **Figure 53. REG 40 (DIE\_TEMP\_FLT)**



LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

# **Table 35. REG 40 (DIE\_TEMP\_FLT) (0x40 Register)**



# <span id="page-55-0"></span>**9 Application and Implementation**

#### **NOTE**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### <span id="page-55-1"></span>**9.1 Application Information**

A typical application consists of the device configured as an  $I^2C$  controlled device and another switch mode charger for Li-Ion and Li-polymer batteries used in a wide range of smart phones and other portable devices. A host controls which charger is enabled during the charging process.

### **9.2 Typical Application**

<span id="page-55-2"></span>

**Figure 54. bq25871 Typical Application**



### **Typical Application (continued)**

#### **9.2.1 Design Requirements**



#### **Table 36. Design Requirement**

#### **9.2.2 Detailed Design Procedure**

The bq25871 continuously monitors battery and adaptor connector temperature by measuring the voltage between TS\_BAT pin and TS\_BUS pins and ground, typically determined by a negative temperature coefficient thermistor and an external voltage divider. The device compares this voltage against its internal thresholds to determine if charging is allowed. To initiate a charging cycle, both battery and connector temperatures must be lower than the temperature threshold, else the device suspends charging and waits until both temperatures are blow the threshold.

Assuming a 103 AT NTC thermistor is used on the battery pack, the values RT1 (connected between TS\_X pin to VREF) and RT2 (connected between TS\_X and ground) can be determined by using the following equations.

$$
\begin{aligned} \text{RT2} &= \frac{V_{\text{REF}} \times \text{RTH}_{\text{COLD}} \times \text{RTH}_{\text{HOT}} \times \left(\frac{1}{V_{\text{LTF}}}-\frac{1}{V_{\text{TCO}}}\right) \\ \text{RTH}_{\text{HOT}} &\times \left(\frac{V_{\text{REF}}}{V_{\text{TCO}}}-1\right) - \text{RTH}_{\text{COLD}} \times \left(\frac{V_{\text{REF}}}{V_{\text{LTF}}}-1\right) \\ \text{RT1} &= \frac{\frac{V_{\text{REF}}}{V_{\text{LTF}}}-1}{\frac{1}{\text{RT2}}+\frac{1}{\text{RTH}_{\text{COLD}}} \end{aligned}
$$

where

 $RTH_{cold}$  and  $V_{LTF}$  are the resistance of NTC under the cold temperature and the corresponding TS\_X pin voltage when charge is allowed,  $RTH<sub>hot</sub>$  and  $V<sub>TCO</sub>$ are the resistance of NTC under the hot temperature and the corresponding TS\_X pin voltage when charge is allowed. (1) **[bq25871](http://www.ti.com/product/bq25871?qgpn=bq25871)** SLUSCQ5 –OCTOBER 2016 **[www.ti.com](http://www.ti.com)**



#### **9.2.3 Application Curves**





### <span id="page-58-0"></span>**10 Power Supply Recommendations**

In order to provide an output voltage on SYS, the device requires a power supply between 3.9-V and 14-V input with at least 100-mA current rating connected to VBUS or a single-cell Li-Ion battery with voltage > VBATUVLO connected to BAT. The source current rating needs to be at least 7.5 A to meet the current capability of the device.

## <span id="page-58-1"></span>**11 Layout**

### <span id="page-58-2"></span>**11.1 Layout Guidelines**

bq25871 supports up to 7-A charge current. It is very critical to maximize Cu trace of VBUS and VOUT. Following PCB layout guideline is recommended:

- Use Cu trace of at least 110 mil (2.794 mm) wide for VBUS and VOUT respectively. This allows current flow evenly through all 7 WCSP solder balls.
- Cu trace of VBUS and VOUT should run at least 150 mil (3.81 mm) straight (perpendicular to WCSP ball array) before making turns.
- Use as large as possible Cu pour for VBUS and VOUT trace elsewhere.
- Use as large as possible Cu pour for PGND.
- Place decoupling capacitors of VBUS and VOUT as close as possible to the device.

### <span id="page-58-3"></span>**11.2 Layout Example**



**Figure 61. bq25871 Layout Diagram (Top Layer)**



**Figure 62. bq25871 Layout Diagram (Mid Layer 2)**



# **Layout Example (continued)**







**Figure 64. bq25871 Layout Diagram (Bottom 1)**



# <span id="page-60-0"></span>**12 Device and Documentation Support**

#### <span id="page-60-1"></span>**12.1 Receiving Notification of Documentation Updates**

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### <span id="page-60-2"></span>**12.2 Community Resources**

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of](http://www.ti.com/corp/docs/legal/termsofuse.shtml) [Use.](http://www.ti.com/corp/docs/legal/termsofuse.shtml)

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#### <span id="page-60-3"></span>**12.3 Trademarks**

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#### <span id="page-60-4"></span>**12.4 Electrostatic Discharge Caution**



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### <span id="page-60-5"></span>**12.5 Glossary**

#### [SLYZ022](http://www.ti.com/lit/pdf/SLYZ022) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.



# <span id="page-61-0"></span>**13 Mechanical, Packaging, and Orderable Information**

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



www.ti.com 10-Dec-2020

# **PACKAGING INFORMATION**



**(1)** The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures. "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

**(3)** MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

**(4)** There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

**(5)** Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

**(6)** Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

# **PACKAGE MATERIALS INFORMATION**

Texas<br>Instruments

# **TAPE AND REEL INFORMATION**





#### **QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**





TEXAS<br>INSTRUMENTS

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 14-Feb-2020



\*All dimensions are nominal





# **PACKAGE OUTLINE**

# **YFF0042 DSBGA - 0.625 mm max height**

DIE SIZE BALL GRID ARRAY



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



# **EXAMPLE BOARD LAYOUT**

# **YFF0042 DSBGA - 0.625 mm max height**

DIE SIZE BALL GRID ARRAY



NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



# **EXAMPLE STENCIL DESIGN**

# **YFF0042 DSBGA - 0.625 mm max height**

DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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